Boosfing

CSE 575: Statistical Machine Learning

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Boosting

Fighting the bias-variance tradeoff

- Simple (a.k.a. weak) learners are good
 - e.g., naïve Bayes, logistic regression, decision stumps (or shallow decision trees) Not Loward
 - Low variance, don't usually overfit
- Simple (a.k.a. weak) learners are bad
 - High bias, can't solve hard learning problems

- Can we make weak learners always good????
 - No!!!
 - But often yes...

Neural retworks are Ensemble model of perceptrons
But not Bust
Voting (Ensemble Methods)

- Instead of learning a single (weak) classifier, learn many weak classifiers that are good at different parts of the input space Space
- Output class: (Weighted) vote of each classifier
 - Classifiers that are most "sure" will vote with more conviction.
 - Classifiers will be most "sure" about a particular part of the space

- On average, do better than single classifier!

Esemble methods creek a team of specialist models

- But how do you ???
 - force classifiers to learn about different parts of the input space?
 - weigh the votes of different classifiers?

Boosting: [Schapire, 1989]

- Idea: given a weak learner, run it multiple times on (reweighted) training data, then let learned classifiers vote
- high error => higher weight On each iteration t:
 - Weigh each training example by how incorrectly it was classified
 - Learn a hypothesis h₊
 - A strength for this hypothesis $\alpha_{\rm t}$ wight of the model

- **Practically useful**
- Theoretically interesting

Learning from weighted data Bocsfig used for both Regression and Classification • Sometimes not all data points are equal but only Classification discussed hee

- Some data points are more important than others
- Consider a weighted dataset
 - D(i) weight of i th training example $(\mathbf{x}^i, \mathbf{y}^i)$
 - Interpretations:
 - *i*th training example counts as D(i) examples
 - If I were to "resample" data, I would get more samples of "heavier" data points
- Now, in all calculations, whenever used, i th training example counts as D(i) "examples"
 - e.g., MLE for Naïve Bayes, redefine Count(Y=y) to be weighted count $\beta(Y=1) = \frac{f(Y=1)}{f(Y=1)}$ by default with D(i) indiable $\beta(Y=0) = (-\hat{\rho}(Y=1))$ $\beta(Y=0) = \frac{f(Y=1)}{f(Y=1)}$ if f(Y=0) oelse

Given:
$$(x_1, y_1), \ldots, (x_m, y_m)$$
 where $x_i \in X, y_i \in Y = \{-1, +1\}$
Initialize $D_1(i) = 1/m$. uniform weight

For $t = 1, \ldots, T$: number

- Train base learner using distribution D_t .
- Get base classifier $h_t: X \to \{-1, +1\}$. Choose $\alpha_t \in \mathbb{R}$. Compute this, method discussed (at., or Update: • Update:
- $D_{t+1}(i) = \frac{D_t(i)\exp(-\alpha_t y_i h_t(x_i))}{Z_t} \text{ a probability}$ where Z_t is a normalization factor correct label=) Z_t where $Z_t = \sum_{i=1}^m D_t(i)\exp(-\alpha_t y_i h_t(x_i))$ and comply the final classifier. Output the final classifier:

 $H(x) = \operatorname{sign}\left(\sum_{t=1}^{T} \alpha_t h_t(x)\right).$

Figure 1: The boosting algorithm AdaBoost.

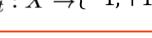
Given: $(x_1, y_1), \ldots, (x_m, y_m)$ where $x_i \in X, y_i \in Y = \{-1, +1\}$ Initialize $D_1(i) = 1/m$.

For t = 1, ..., T:

- Train base learner using distribution D_t .
- Get base classifier $h_t: X \to \{-1, +1\}$.

$$t \in \mathbb{R}$$
.

$$t \in \mathbb{R}$$
. \leftarrow





$$--\alpha_t$$

$$-\alpha_t$$
 =

$$h_t(x_i)$$

$$a_t(x_i)$$

$$t(x_i)$$

 $\epsilon_t = P_{i \sim D_i}[\mathbf{x}^i \neq y^i]$

 $\epsilon_t = \frac{1}{\sum_{i=1}^m D_t(i)} \sum_{i=1}^m D_t(i) \delta(h_t(x_i) \neq y_i)$

Lish to below $D_{t+1}(i) = \frac{D_t(i) \exp(-\alpha_t y_i h_t(x_i))}{Z_t}$ this point for the high disassion

What α_t to choose for hypothesis h_t ? Every to understand your bound on training error [Schapire, 1989]

[Schapire, 1989]

Training error of final classifier is bounded by:

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$$\frac{1}{m}\sum_{i=1}^{m}\delta(H(x_{i})\neq y_{i})\leq \frac{1}{m}\sum_{i=1}^{m}\exp(-y_{i}f(x_{i}))$$

$$\lim_{i=1}^{m}\delta(H(x_{i})\neq y_{i})\leq \frac{1}{m}\sum_{i=1}^{m}\exp(-y_{i}f(x_{i}))$$

What α_t to choose for hypothesis h_t ?

[Schapire, 1989]

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$$\frac{1}{m} \sum_{i=1}^{m} \delta(H(x_i) \neq y_i) \leq \frac{1}{m} \sum_{i=1}^{m} \exp(-y_i f(x_i)) = \prod_{t} Z_t$$
Where $f(x) = \sum_{t} \alpha_t h_t(x)$; $H(x) = sign(f(x))$

$$Z_t = \sum_{i=1}^m D_t(i) \exp(-\alpha_t y_i h_t(x_i))$$

$$\text{NO proof}_1 \text{ first result}_2$$

$$\text{"not difficult to prove"}_1$$

$$\text{visit office Hours for non-}_2$$

$$\text{Jet ail}_1$$

What α_t to choose for hypothesis h_t ?

[Schapire, 1989]

Training error of final classifier is bounded by:

$$\frac{1}{m} \sum_{i=1}^{m} \delta(H(x_i) \neq y_i) \leq \frac{1}{m} \sum_{i} \exp(-y_i f(x_i)) = \prod_{t} Z_t$$

Where
$$f(x) = \sum_{t} \alpha_t h_t(x)$$
; $H(x) = sign(f(x))$

If we minimize
$$\Pi_t Z_t$$
, we minimize our training error directly?

We can tighten this bound greedily, by choosing α_t and h_t on each iteration to minimize $Z_t = \lim_{t \in \mathcal{A}} \sum_{t \in$

$$Z_t = \sum_{i=1}^m D_t(i) \exp(-\alpha_t y_i h_t(x_i))$$

What α_t to choose for hypothesis h_t ?

[Schapire, 1989]

We can minimize this bound by choosing α_t on each iteration to minimize Z_t

$$Z_t = \sum_{i=1}^m D_t(i) \exp(-\alpha_t y_i h_t(x_i))$$

For binary weak classifiers, this is accomplished by [Freund & Schapire '97]:

$$\alpha_t = \frac{1}{2} \ln \left(\frac{1 - \epsilon_t}{\epsilon_t} \right)$$

Sample Test Question: How to prove it?

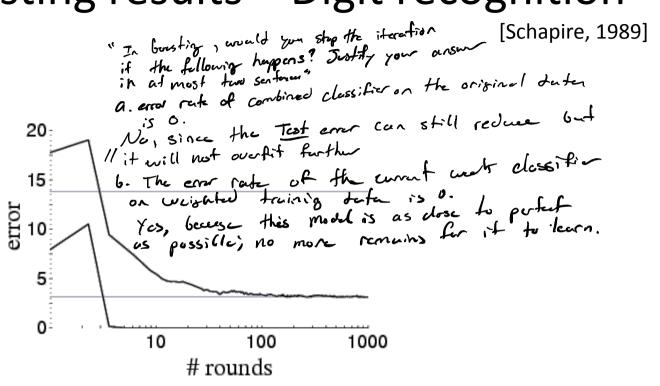
1 Sany

take partial derivative a la MLE

- If each classifier is (at least slightly) better than random $-\epsilon_{t} < 0.5$
- AdaBoost will achieve zero training error (exponentially fast):

$$\frac{1}{m} \sum_{i=1}^{m} \delta(H(x_i) \neq y_i) \leq \prod_{t=1}^{m} Z_t \leq \exp\left(-2 \sum_{t=1}^{m} (1/2 - \epsilon_t)^2\right)$$

Boosting results - Digit recognition

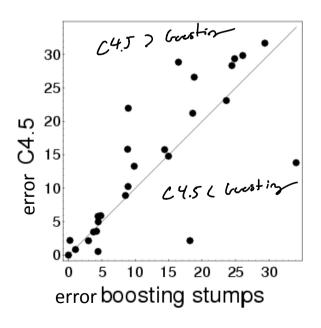


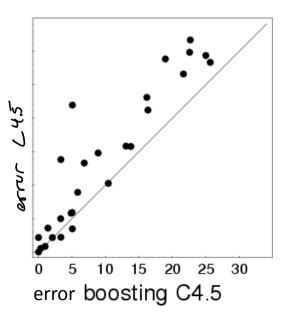
- Boosting often
 - Robust to overfitting
 - Test set error decreases even after training error is zero

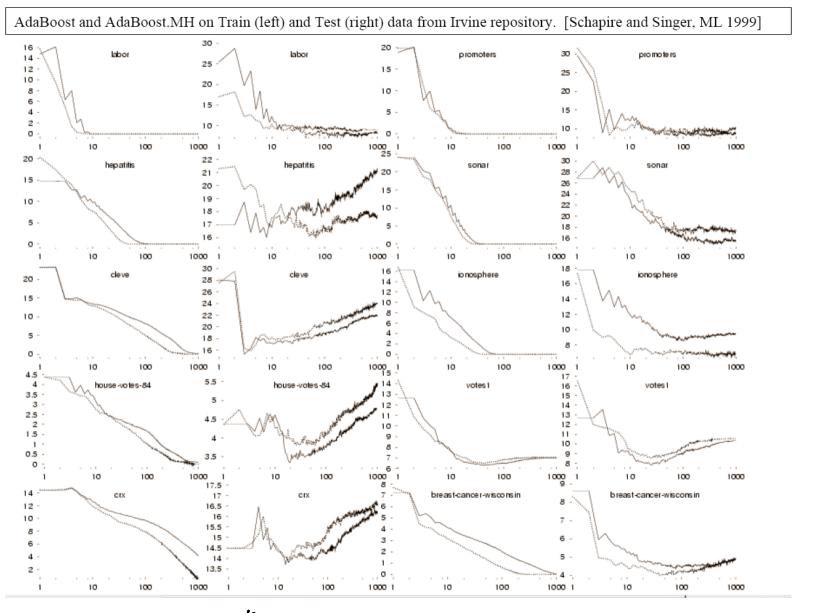
Boosting: Experimental Results

[Freund & Schapire, 1996]

Comparison of C4.5, Boosting C4.5, Boosting decision stumps (depth 1 trees), 27 benchmark datasets









Boosting and Logistic Regression

Logistic regression assumes:

$$P(Y = 1|X) = \frac{1}{1 + \exp(f(x))}$$

And tries to maximize data likelihood:

$$P(\mathcal{D}|H) = \prod_{i=1}^{m} \frac{1}{1 + \exp(-y_i f(x_i))}$$

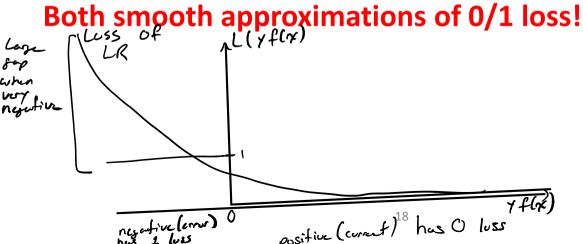
Equivalent to minimizing log loss
$$\sum_{i=1}^{m} \frac{\ln(1+\exp(-y_i f(x_i)))}{\exp(is^{-7}\log is^{-7}\log is^{-1}\log is^{-1})}$$

Boosting and Logistic Regression

Logistic regression equivalent to minimizing log loss

$$\sum_{i=1}^{m} \ln(1 + \exp(-y_i f(x_i)))$$

Boosting minimizes similar loss function!!
$$\frac{1}{m} \sum_{i} \exp(-y_i f(x_i)) = \prod_{t} Z_t$$



LR: flx)= & w: x;

Bousting: flx)= & xchelx)

sign (f(x)) = (+1 iff(x) > 0

-1 if f(x) co LR: Loss 1 n (1+ expl-yf(x))

that to optimize

Logistic regression and Boosting

Logistic regression:

Minimize loss fn

$$\sum_{i=1}^{m} \ln(1 + \exp(-y_i f(x_i)))$$

Define

$$f(x) = \sum_{j} w_j x_j$$

where x_i predefined

Boosting:

Minimize loss fn

$$\sum_{i=1}^{m} \exp(-y_i f(x_i))$$

Define

$$f(x) = \sum_{t} \alpha_t h_t(x)$$

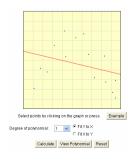
where $h_t(x_i)$ defined dynamically to fit data (not a linear classifier)

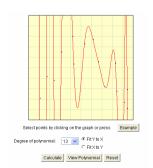
• Weights α_t learned incrementally

OK... now we'll learn to pick those darned parameters...

- Selecting features (or basis functions)
 - Linear regression
 - Naïve Bayes
 - Logistic regression
- Selecting parameter value
 - Prior strength
 - Naïve Bayes, linear and logistic regression
 - Regularization strength
 - Naïve Bayes, linear and logistic regression
 - Decision trees
 - MaxpChance, depth, number of leaves
 - Boosting
 - Number of rounds
- These are called Model Selection Problems

Test set error as a function of model complexity





Simple greedy model selection algorithm

- Pick a dictionary of features
 - e.g., polynomials for linear regression
- Greedy heuristic:
 - Start from empty (or simple) set of features $F_0 = \emptyset$
 - Run learning algorithm for current set of features F_t
 - Obtain h_t
 - Select next best feature X_i
 - e.g., X_j that results in lowest training error learner when learning with F_t U $\{X_j\}$
 - $-F_{t+1} \leftarrow F_t \cup \{X_i\}$
 - Recurse

Greedy model selection

- Applicable in many settings:
 - Linear regression: Selecting basis functions
 - Naïve Bayes: Selecting (independent) featuresP(X_i|Y)
 - Logistic regression: Selecting features (basis functions)
- Only a heuristic!
- There are many more elaborate methods out there

Simple greedy model selection algorithm

- Greedy heuristic:
 - **–** ...
 - Select next best feature X_i
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When do you stop???

When training error is low enough?

Simple greedy model selection algorithm

- Greedy heuristic:
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When do you stop???

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- When test set error is low enough?

Validation set

- Thus far: Given a dataset, randomly split it into two parts:
 - Training data $\{\mathbf{x}_1, ..., \mathbf{x}_{Ntrain}\}$
 - Test data $\{\mathbf{x}_1, ..., \mathbf{x}_{Ntest}\}$
- But Test data must always remain independent!
 - Never ever ever learn on test data, including for model selection
- Given a dataset, randomly split it into three parts:
 - Training data $\{\mathbf{x}_1, ..., \mathbf{x}_{Ntrain}\}$
 - Validation data $\{\mathbf{x}_1, ..., \mathbf{x}_{Nvalid}\}$
 - Test data $\{\mathbf{x}_1, ..., \mathbf{x}_{Ntest}\}$
- Use validation data for tuning learning algorithm, e.g., model selection
 - Save test data for very final evaluation

Simple greedy model selection algorithm

- Greedy heuristic:
 - **–** ...
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 - e.g., X_j that results in lowest training error learner when learning with F_t U {X_i}
 - $-F_{i}$ F_{i} $U\{X_{j}\}$
 - Recurse

When do you stop???

- When training error is low enough?
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Simple greedy model selection algorithm

- Greedy heuristic:
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When do you stop???

- When training error is low enough?
- When test set error is low enough?
- When validation set error is low enough?
- Man!!! OK, should I just repeat until I get tired???
 - □ I am tired now...
 - □ No, "There is a better way!"

(LOO) Leave-one-out cross validation

- Consider a validation set with 1 example:
 - D training data
 - D\i training data with i th data point moved to validation set
- Learn classifier h_{D\i} with D\i dataset
- Estimate true error as:
 - 0 if $h_{D\setminus i}$ classifies *i* th data point correctly
 - 1 if $h_{D\setminus i}$ is wrong about *i* th data point
 - Seems really bad estimator, but wait!
- **LOO cross validation**: Average over all data points *i*:
 - For each data point you leave out, learn a new classifier $h_{D\setminus i}$
 - Estimate error as:

$$error_{LOO} = \frac{1}{m} \sum_{i=1}^{m} \mathbb{1} \left(h_{\mathcal{D}\setminus i}(\mathbf{x}^i) \neq y^i \right)$$

LOO cross validation is (almost) unbiased estimate of true error!

- When computing **LOOCV** error, we only use *m-1* data points
 - So it's not estimate of true error of learning with m data points!
 - Usually pessimistic, though learning with less data typically gives worse answer
- LOO is almost unbiased!
 - Let $error_{true \, m-1}$ be true error of learner when you only get m-1 data points
 - LOO is unbiased estimate of error_{true,m-1}:

$$E_{\mathcal{D}}[error_{LOO}] = error_{true,m-1}$$

- Great news!
 - Use LOO error for model selection!!!

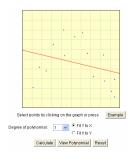
Simple greedy model selection algorithm

- Greedy heuristic:
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 - e.g., X_j that results in lowest training error learner when learning with F_t U {X_i}
 - $-F_{i}$ F_{i} $U\{X_{j}\}$
 - Recurse

When do you stop???

- When training error is low enough?
- When test set error is low enough?
- When validation set error is low enough?
- STOP WHEN error_{LOO} IS LOW!!!

Using LOO error for model selection





Computational cost of LOO

- Suppose you have 100,000 data points
- You implemented a great version of your learning algorithm
 - Learns in only 1 second
- Computing LOO will take about 1 day!!!
 - If you have to do so for each choice of basis functions, it will take fooooooreeever!!!
- Solution 1: Preferred, but not usually possible
 - Find a cool trick to compute LOO

Solution to complexity of computing LOO:

(More typical) Use k-fold cross validation

- Randomly divide training data into k equal parts
 - $D_1,...,D_k$
- For each *i*
 - Learn classifier $h_{D\setminus Di}$ using data point not in D_i
 - Estimate error of $\hat{h}_{D \setminus Di}$ on validation set D_i :

$$error_{\mathcal{D}_i} = \frac{k}{m} \sum_{(\mathbf{x}^j, y^j) \in \mathcal{D}_i} \mathbb{1} \left(h_{\mathcal{D} \setminus \mathcal{D}_i}(\mathbf{x}^j) \neq y^j \right)$$

k-fold cross validation error is average over data splits:

$$error_{k-fold} = \frac{1}{k} \sum_{i=1}^{k} error_{\mathcal{D}_i}$$

- k-fold cross validation properties:
 - Much faster to compute than LOO

- More (pessimistically) biased - using much less data, only $m(k-1)/k \leftarrow$

Know Low Jefinifier Complexity cost of Low Poly fold how it relates to Loo

no free lunch